N-channel TrenchMOS logic level FET

Rev. 06 — 15 June 2009

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Suitable for high frequency applications due to fast switching characteristics
- Suitable for logic level gate drive sources

DC-to-DC convertors

1.3 Applications

- Computer motherboards

1.4 Quick reference data

Table 1.	Quick reference					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	25	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	75	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	107	W
Dynamic	characteristics					
Q _{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 12 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	4	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } Figure 7;$ see Figure 8	-	7.65	9	mΩ



2. Ordering information

Table 2. Ordering information							
Type number							
	Name	Description	Version				
PHU78NQ03LT	IPAK	plastic single-ended package (IPAK); 3 leads (in-line)	SOT533				

3. Pinning information

Table 3.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		-
2	D	drain	mb	
3	S	source	G	
mb	D m	mounting base; connected to drain		mbb076 S
			SOT533 (IPAK)	

Limiting values 4.

Limiting values Table 4.

In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions	Min	Max	Unit
drain-source voltage	T _i ≥ 25 °C; T _i ≤ 175 °C	-	25	V
drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega; T_{mb} \ge 25 \text{ °C}; T_{mb} \le 175 \text{ °C}$	-	25	V
gate-source voltage		-20	20	V
drain current	V _{GS} = 5 V; T _{mb} = 100 °C	-	46.9	А
	V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	57.5	А
	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1;</u> see <u>Figure 3</u>	-	75	А
	V _{GS} = 5 V; T _{mb} = 25 °C	-	66.4	А
peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	240	А
total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	107	W
storage temperature		-55	175	°C
junction temperature		-55	175	°C
ain diode				
source current	T _{mb} = 25 °C	-	75	А
peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	240	А
ruggedness				
	drain-source voltage drain-gate voltage gate-source voltage drain current peak drain current total power dissipation storage temperature junction temperature ain diode source current	$\begin{array}{ll} \mbox{drain-source voltage} & T_j \geq 25 \ {}^\circ\mbox{C}; \ T_j \leq 175 \ {}^\circ\mbox{C} \\ \mbox{drain-gate voltage} & R_{GS} = 20 \ k\Omega; \ T_{mb} \geq 25 \ {}^\circ\mbox{C}; \ T_{mb} \leq 175 \ {}^\circ\mbox{C} \\ \mbox{gate-source voltage} \\ \mbox{drain current} & \frac{V_{GS} = 5 \ V; \ T_{mb} = 100 \ {}^\circ\mbox{C} \\ V_{GS} = 10 \ V; \ T_{mb} = 100 \ {}^\circ\mbox{C}; \ see \ Figure 1 \\ V_{GS} = 10 \ V; \ T_{mb} = 25 \ {}^\circ\mbox{C}; \ see \ Figure 1 \\ V_{GS} = 5 \ V; \ T_{mb} = 25 \ {}^\circ\mbox{C}; \ see \ Figure 2 \\ \mbox{v}_{GS} = 5 \ V; \ T_{mb} = 25 \ {}^\circ\mbox{C}; \ see \ Figure 3 \\ V_{GS} = 5 \ V; \ T_{mb} = 25 \ {}^\circ\mbox{C}; \ see \ Figure 3 \\ \mbox{total power dissipation} & T_{mb} = 25 \ {}^\circ\mbox{C}; \ see \ Figure 2 \\ \mbox{storage temperature} \\ \mbox{junction temperature} \\ \mbox{junction temperature} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{p} \leq 10 \ \mu\mbox{s; pulsed; } T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{p} \leq 10 \ \mu\mbox{s; pulsed; } T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{p} \leq 10 \ \mu\mbox{s; pulsed; } T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{p} \leq 10 \ \mu\mbox{s; pulsed; } T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{C} \\ \mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{peak source current} & T_{mb} = 25 \ {}^\circ\mbox{peak source current} & T_{mb} = 25 \ {}^\circpeak$	$\begin{tabular}{ c c c } & T_j \ge 25 \ \end{tabular}^C; \ T_j \le 175 \ \end{tabular}^C & - & & & & & & & & & & & & & & & & & $	$ \begin{array}{cccccccccccccccccccccccccccccccccccc$

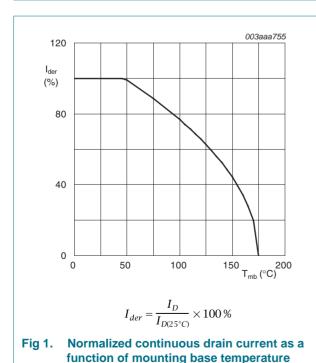
non-repetitive E_{DS(AL)S}

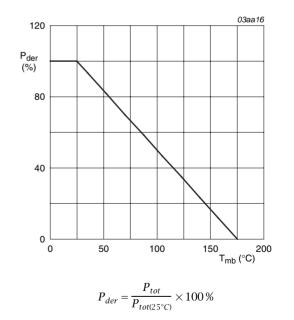
 V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 32 A; $V_{sup} \le$ 25 V; drain-source avalanche unclamped; $t_p = 0.17 \text{ ms}$; $R_{GS} = 50 \Omega$



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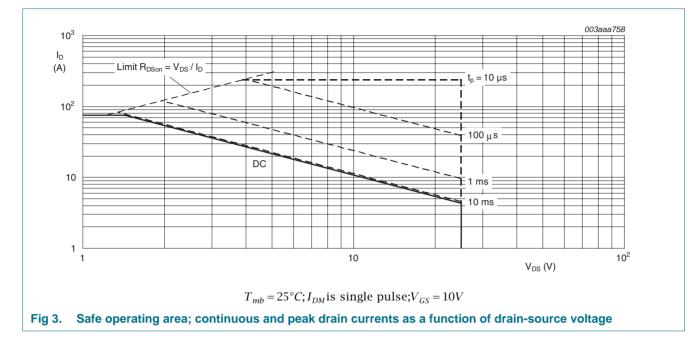
energy







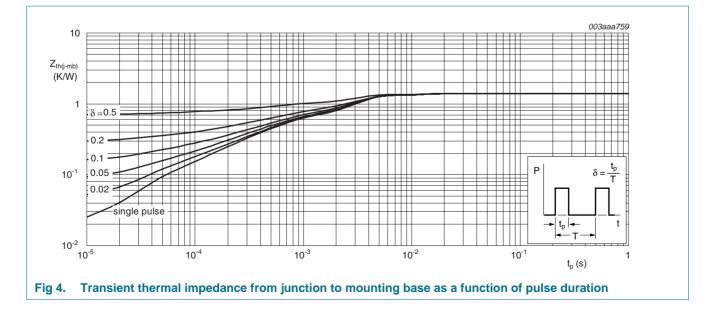
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5. Thermal characteristics

Table 5.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	-	1.4	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in free air	-	70	-	K/W

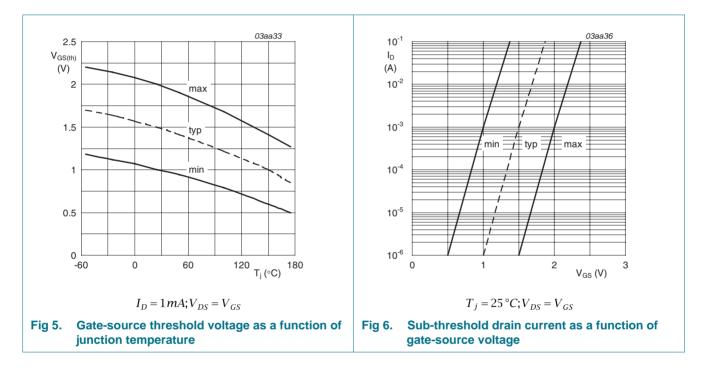


6. Characteristics

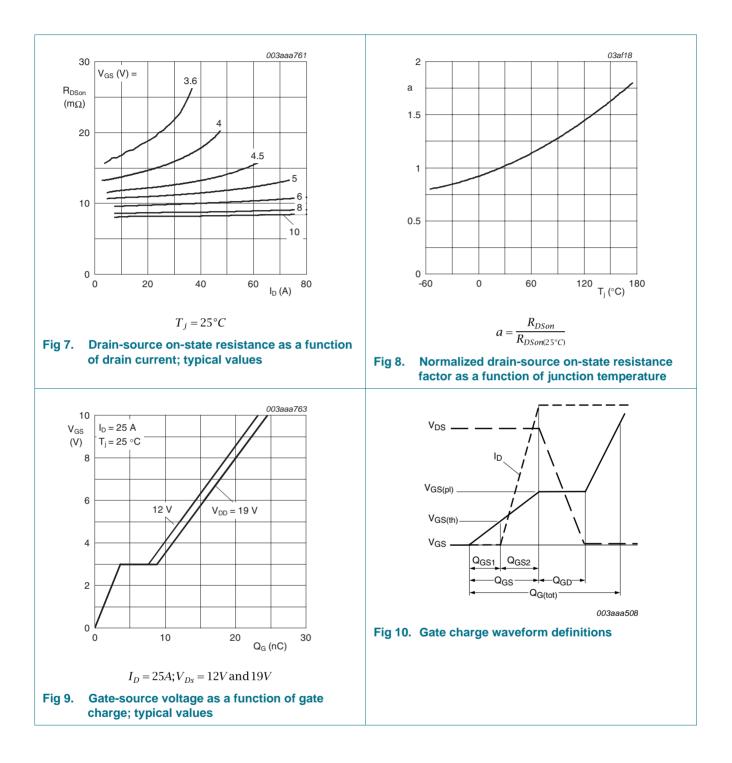
Table 6.	Characteristics						
Symbol	Parameter	Conditions	Min	Тур	Max	Unit	
Static cha	Static characteristics						
$V_{(BR)DSS}$	drain-source	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ C$	22	-	-	V	
	breakdown voltage	$I_D = 250 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$	25	-	-	V	
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see <u>Figure 5</u> ; see <u>Figure 6</u>	-	-	2.2	V	
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see <u>Figure 5</u> ; see <u>Figure 6</u>	0.5	-	-	V	
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 5</u> ; see <u>Figure 6</u>	1	1.5	2	V	
I _{DSS}	drain leakage current	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	-	1	μΑ	
		$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ	
I _{GSS}	gate leakage current	V_{GS} = 15 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA	
		V_{GS} = -15 V; V_{DS} = 0 V; T_j = 25 °C	-	10	100	nA	
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 7</u> ; see <u>Figure 8</u>	-	7.65	9	mΩ	
		V _{GS} = 5 V; I _D = 25 A; T _j = 175 °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	-	18.9	24.3	mΩ	
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see <u>Figure 7</u> ; see <u>Figure 8</u>	-	10.5	13.5	mΩ	
R_{G}	internal gate resistance (AC)	f = 1 MHz; T _j = 25 °C	-	1	-	Ω	
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V};$ $T_j = 25 \text{ °C}$	-	8.6	-	nC	
		$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$ $T_j = 25 \text{ °C}; \text{ see } Figure 9; \text{ see } Figure 10$	-	11	-	nC	
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; V_{GS} = 4.5 \text{ V};$	-	3.6	-	nC	
Q _{GS1}	pre-threshold gate-source charge	$T_j = 25 \text{ °C}; \text{ see } Figure 10; \text{ see } Figure 10$	-	1.8	-	nC	
Q _{GS2}	post-threshold gate-source charge		-	1.8	-	nC	
Q_{GD}	gate-drain charge		-	4	-	nC	
V _{GS(pl)}	gate-source plateau voltage	$I_D = 25 \text{ A}; V_{DS} = 12 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	-	3	-	V	
C _{iss}	input capacitance	V_{DS} = 12 V; V_{GS} = 0 V; f = 1 MHz;	-	970	-	pF	
		$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 11}{\text{Figure } 11}$	-	1460	-	pF	
C _{oss}	output capacitance		-	415	-	pF	
C _{rss}	reverse transfer capacitance		-	170	-	pF	

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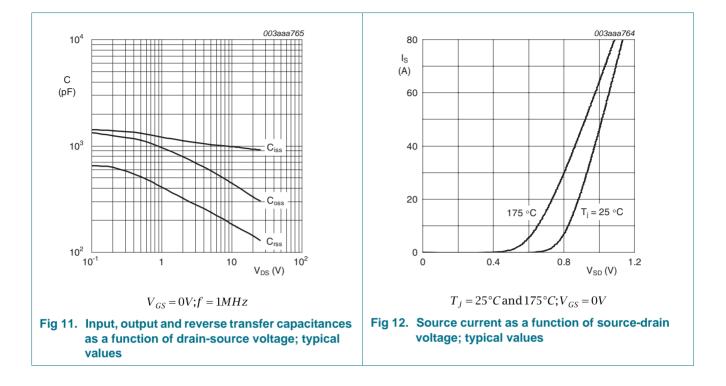
Table 6.	Characteristics continued					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t _{d(on)}	turn-on delay time	$V_{DS} = 12 \text{ V}; \text{ R}_{L} = 0.5 \Omega; \text{ V}_{GS} = 5 \text{ V};$	-	13	-	ns
t _r	rise time	$R_{G(ext)} = 5.6 \ \Omega; T_j = 25 \ ^{\circ}C$	-	46	-	ns
t _{d(off)}	turn-off delay time		-	20	-	ns
t _f	fall time		-	15	-	ns
Source-d	rain diode					
V_{SD}	source-drain voltage	I _S = 25 A; V _{GS} = 0 V; T _j = 25 °C; see <u>Figure 12</u>	-	0.78	1.2	V
t _{rr}	reverse recovery time	$I_{S} = 20 \text{ A}; \text{ d}I_{S}/\text{d}t = -100 \text{ A}/\mu\text{s}; \text{ V}_{GS} = 0 \text{ V};$	-	35	-	ns
Qr	recovered charge	V _{DS} = 25 V; T _j = 25 °C	-	20	-	nC



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7. Package outline

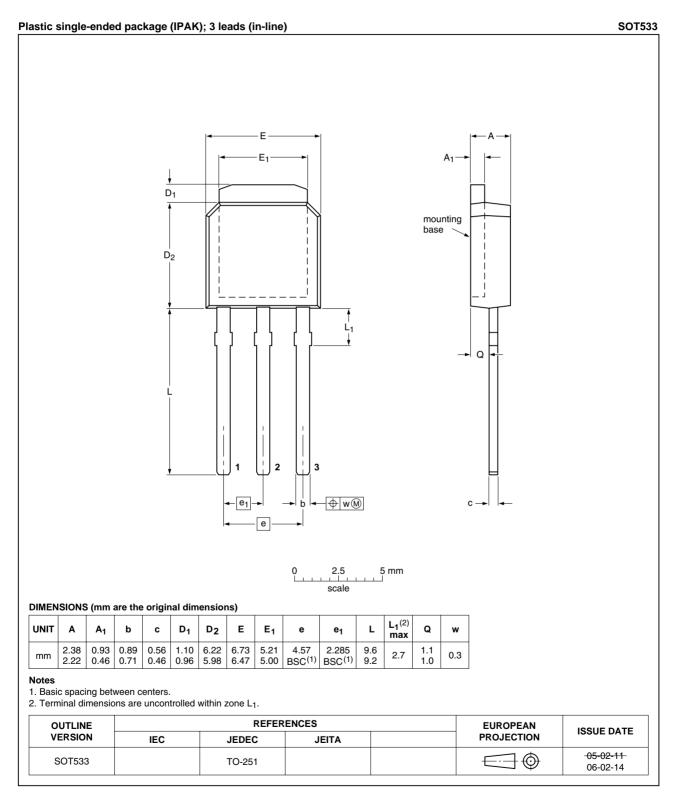


Fig 13. Package outline SOT533 (IPAK)

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PHU78NQ03LT_6	20090615	Product data sheet		PHU_PHD78NQ03LT_5
Modifications:		of this data sheet has beer of NXP Semiconductors.	n redesigned to comply w	ith the new identity
	 Legal texts 	have been adapted to the	new company name whe	re appropriate.
	 Type number 	er PHU78NQ03LT separate	ed from data sheet PHU_	PHD78NQ03LT_5.
PHU_PHD78NQ03LT_5 (9397 750 15084)	20050727	Product data sheet	-	PHP_PHU78NQ03LT_4
PHP_PHU78NQ03LT_4 (9397 750 13431)	20040726	Product data sheet	-	PHP_PHB_PHD78NQ03 LT-03
PHP_PHB_PHD78NQ03 LT-03 (9397 750 09667)	20020626	Product data	-	PHP_PHB_PHD78NQ03 LT-02
PHP_PHB_PHD78NQ03 LT-02 (9397 750 09418)	20020322	Product data	-	PHP_PHB_PHD78NQ03 LT-01
PHP_PHB_PHD78NQ03 LT-01 (9397 750 08916)	20011114	Product data	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions"

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